

ABSTRACT OF THE DISCLOSURE

A simulation apparatus configured to estimate properties of a semiconductor device, comprising: a first calculating part configured to calculate a first value
5 corresponding to a prescribed physical property value by taking a prescribed physical quantity into consideration, with regard to at least a partial region of said semiconductor device; a second calculating part configured to calculate a second value corresponding to said physical property value
10 without taking said physical quantity into consideration, with regard to at least a partial region of said semiconductor device, and a visualizing part configured to display, in a prescribed form, a correlation between said first and second values.

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